

ISO/IEC 24789-2:2011-11 (E)

Identification cards - Card service life - Part 2: Methods of evaluation

| Contents | | Page |
|-------------------------------------------------------|------------------------------------------------------------------------|-------------|
| Foreword | | iv |
| Introduction | | v |
| 1 | Scope | 1 |
| 2 | Normative references | 1 |
| 3 | Terms, definitions and abbreviated terms | 2 |
| 3.1 | Terms and definitions | 2 |
| 3.2 | Abbreviated terms | 2 |
| 4 | Default items applicable to the evaluation methods | 2 |
| 4.1 | Test environment | 2 |
| 4.2 | Pre-conditioning | 2 |
| 4.3 | Selection of evaluation methods | 2 |
| 4.4 | Default tolerance | 2 |
| 4.5 | Total measurement uncertainty | 2 |
| 5 | Methods of evaluation for card service life (CSL) | 3 |
| 5.1 | Xenon arc light exposure | 3 |
| 5.2 | Surface abrasion | 4 |
| 5.3 | Magnetic stripe abrasion | 5 |
| 5.4 | ICM adhesion | 8 |
| 5.5 | Plasticised vinyl storage | 9 |
| 5.6 | Wear and soil test | 10 |
| 5.7 | Temperature and humidity aging | 13 |
| 5.8 | Temperature shock | 13 |
| 5.9 | Temperature and humidity cycling | 14 |
| 5.10 | ID-1 card flexure | 16 |
| 5.11 | Temperature and humidity aging followed by peel strength testing | 17 |
| 5.12 | Cross-cut test | 18 |
| Annex A (informative) Shortened bendings method | | 21 |
| Bibliography | | 23 |